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PATENT

IN THE UNITED STATES PATENT AND TRADEMARK OFFICE

Applicant	:	Zhimin Lu	)	Group Art Unit Unknown
			)	
Appl. No.	:	09/870,393	)	I hereby certify that this correspondence and all
			)	marked attachments are being deposited with
Filed	:	May 29, 2001	)	the United States Postal Service as first-class
			)	mail in an envelope addressed to: United States
For	:	METHOD AND APPARATUS	)	Patent and Trademark Office, P.O. Box 2327,
		TO CORRECT WAFER DRIFT	)	Arlington, VA 22202, on
			)	
Examiner	:	Unknown	)	<u>August 2, 2002</u>
			)	(Date)
			)	<u>Adeel S. Akhtar, Reg. No. 41,394</u>

PRELIMINARY AMENDMENT

United States Patent and Trademark Office  
P.O. Box 2327  
Arlington, VA 22202

Dear Sir:

Prior to examination on the merits, please amend the above-captioned application as follows:

IN THE SPECIFICATION:

Please amend the paragraph beginning on p. 16, line 3, as indicated in the replacement paragraph below:

The deviation in voltage readings are used to calculate 630 offsets  $\Delta_L$  and  $\Delta_R$ .  $\Delta_L$  and  $\Delta_R$  represent the linear deviations from the nominal wafer position, as measured longitudinally along the sensors (see Figure 12).  $\Delta_L$  and  $\Delta_R$  may be obtained from the following equation:

$$\Delta = \frac{l_{\max} - l_{\min}}{V_{\max} - V_{\min}} (V_{\text{ref}} - V)$$

Here,  $l_{\max}$  and  $l_{\min}$  represent maximum and minimum sensor laser beam lengths left unblocked by the wafer,  $V_{\max}$  and  $V_{\min}$  represent the output value of the sensors when  $l_{\max}$  and  $l_{\min}$  are left unblocked,  $V_{\text{ref}}$  indicates the sensor output value when the reference wafer is at the nominal